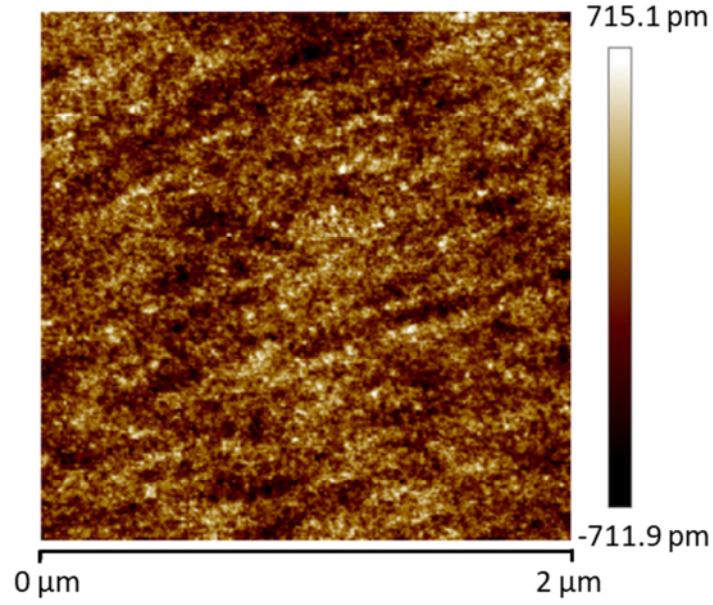


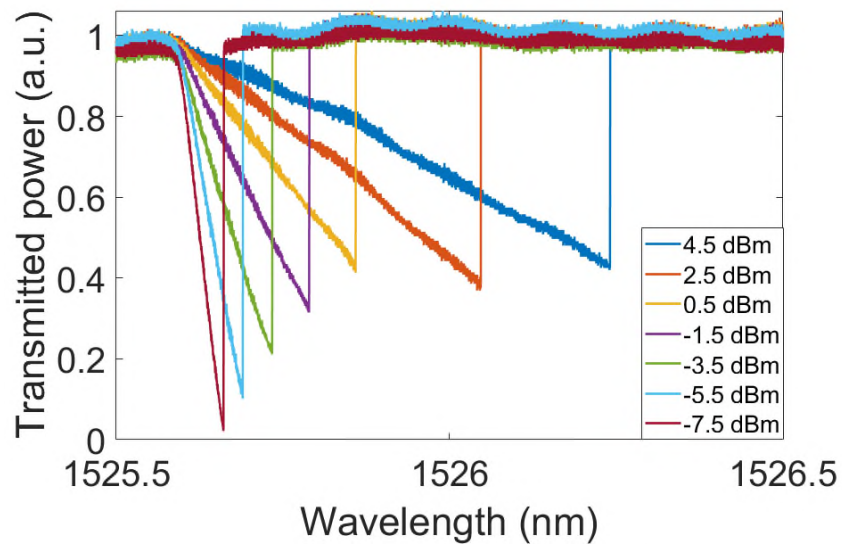
Supplementary Information

Ultra-efficient frequency comb generation in AlGaAs-on-insulator microresonators

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Supplementary Figure 1: Surface roughness characterization. Surface profile of the epi wafer measured by Atomic Force Microscope (AFM). The Root Mean Square (RMS) roughness is ~ 0.2 nm.



Supplementary Figure 2: Thermal triangle measurement. Measured thermal triangles of a 450 GHz resonator under different on-chip power levels.